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A) AFM Cantilevers and material variations

→ High Softness	Probes with extraordinary → High Stiffness	\rightarrow High Fre	•	
	AFM Tip: Silicon	Radius [nm] < 1	0 (PPP) / < 5 (SSS ¹))
		Height [µm] 10	. , . ,	/
	AFM Cantilevers: Silicon		s are available:	
		SD-T1L450	SD-T1L450B	SD-T1L225
	Resonance Frequency [kHz]	6	6	25
	Force Constant [N/m]	0.01	0.02	0.1
	CB length [µm]	450	450	225
	CB width [µm]	23	48	23
	CB thickness [µm]	1.0	1.0	1.0
50 µm	Coating	-	-	-
		SD-T2L125	SD-T5L450B	SD-T5L225
	Resonance Frequency [kHz]	150	35	130
	Force Constant [N/m]	2	3	14
	CB length [µm]	125	450	225
	CB width [µm]	25	58	33
	CB thickness [µm]	2.0	5.0	5.0
	Coating	70 nm Au on detector side (optional)	-	-
	,	SD-T7L100	SD-T10L100	SD-NCVH
	Resonance Frequency [kHz]	850	1'000	1'200
	Force Constant [N/m]	600	2'000	66
	CB length [µm]	100	100	45
	CB width [µm]	38	45	25
	CB thickness [µm]	7.0	10.0	1.8
	Coating	30 nm Al	on detector side (op	tional)
		SD-SSS-T10L2501	SD-TL-T4L90 ²	
	Resonance Frequency [kHz]	220	680	
	Force Constant [N/m]	120	110	
	CB length [µm]	250	90	
	CB width [µm]	45	30	
	CB thickness [µm]	10.0	4.0	
	Coating	-	-	
	_	rpSilicon (SSS) AFM		/

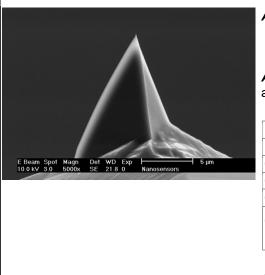
AFM Support chip: Silicon



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Phosphorus doped PointProbePlus (PPP) AFM Probes



AFM Tip: Phosphorus dop	ed Silicon		
	Radius [nm]	< 10	
	Height [µm]	10 - 15	
AFM Cantilevers: Phosph available:	orus doped S	Silicon. Different v	ersions are
	SD-P-NCH*	SD-P-FM	SD-P-CONT
Resonance Frequency [kHz]	330	75	13
Force Constant [N/m]	42	2.8	0.2
CB length [µm]	125	225	450
CB width [µm]	30	28	50
CB thickness [µm]	4.0	3.0	2.0
Coating	30 nm Al on detector side (optional)		-

*Optional: Rotated AFM tip

AFM Support chip: Phosphorus doped Silicon

Low Q- / High Q-Factor AFM Probes AFM Tip: Silicon Radius [nm] < 10 Height [µm] 10 - 15 AFM Cantilevers: Silicon. Different versions are available: SD-LQNCHR SD-QNCHR SD-QFMR Resonance Frequency [kHz] 330 330 75 Force Constant [N/m] 42 42 2.8 125 125 225 CB length [µm] CB width [µm] 28 30 30 CB thickness [µm] 4.0 4.0 3.0 Coating 30 nm Al on detector side (partial coating) **Q-Factor in UHV** 2'000 >30'000 AFM Support chip: Silicon



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B) Special Coatings

M Cantil		bePlus, Arro	w, ATEC,
	evers: N		
M Suppo		NC, FM, CON	ΙΤ,
in Cappe	ort chips	s: Silicon, Py	rex
-	Side:	additional ma frontside (Tip	Cr, FeNi, Ir, Ni, NiCo, Pt, Rh, Ti <i>aterials available upon request</i> pSide, TS), backside (DetectorSide, DS) BothSides, BS)
			coating thickness and AFM probe inical problems)
amples:			25 nm Au (TS) / 70 nm Au (DS) 40 nm Tungsten (TS) / 40 nm Tungsten + 30 nm Al (DS)
	SD-EF	M60:	40 nm Pt (BS) 60 nm Pt (BS)
			60 nm Al (DS) non-conductive Diamond coating (TS)
	SD-DT	-NCL:	non-conductive Diamond caoting (TS)
	me restr es coulo	Side: me restrictions es could occur amples: SD-NC SD-CC SD-CC SD-EF SD-ZE SD-DT SD-DT	additional ma Side: frontside (Tip both sides (E

Partial Coatings of AFM Cantileve	ers	
	Coatings: Material:	Ag, Al, Au, Cr, FeNi, Ir, Ni, NiCo, Pt, Rh,Ti additional materials available upon request
	Side:	frontside (TipSide, TS), backside (DetectorSide, DS), both sides (BothSides, BS)
	Minimal feature size:	10 µm
Pt	Alignment accuracy:	~ 5 µm
	Note: Reflex coating on ATEC is	s possible



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PointProbePlus (PPP) AFM Probes with very thin Silicon Nitride layer

	AFM Tip: Silicon	Radius [nm]	< 20	
		Height [µm]	10 - 15	
		Coating	10 nm Silicon	Nitride
	Other AFM tips / c	oating thickn	esses availal	ble on request
1 Ale	AFM Cantilevers: Silicon.	Different ver	sions are av	ailable:
		SD-FN	A-SiN	SD-CONT-SiN*
	Resonance Frequency [kHz]	75	5	13
	Force Constant [N/m]	2.	8	0.2
	CB length [µm]	22	5	450
	CB width [µm]	28	3	50
	CB thickness [µm]	3.	0	2.0
	Coating		70 nm Au on de	etector side
	Other mecha	nical propert	ies available	* Rotated tip on request
	AFM Support chip: Silico			



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C) AFM Tips modifications

	Biotool		ſ	SD-qp-BioAC- Bio	SD-qp-BioAC- BioXXL
A			Radius [nm]	25	25
			Height [µm]	Quartz.: 6.5 DLC: 0.5	Quartz.: 6.5 DLC: 8.5
			Orientation [°]	0	12 (tilt compensated
			SD-qp-B	oAC-Bio / SD-qp-	BioAC-BioXXL
			SD-qp-B	oAC-Bio / SD-qp-	BioAC-BioXXL
		Resonance Frequency [kHz]		50	
	Biotool	Force Constant [N/m]		0.1	
A	XXL	CB length [µm]		60	
		CB width [µm]		25	
- M		CB thickness [µm]		0.4	
		Coating tip side	20 nr	n Au (spike remain	s uncoated)
		Coating detector side		70 nm Au	
ese AFM probes have been o laboration with nanotools®	leveloped in	AFM Support chip: Silico Also a		gh nanotools [®]	

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Carbon NanoTip					
	AFM Tip: Silicon / High D	ense Diamon	d Like Carb	oon (DLC) s	pike
		Radius [nm]	2 (< 5 guara	inteed)	
		Height [µm]	Si : 10 - 15 /	DLC : 0.125	
		Orientation [°]	13 (tilt comp	ensated)	
	AFM Cantilevers: Silicon	1	·		
		SD-aCN	T-NCH	SD-aC	NT-FM
	Resonance Frequency [kHz]	33			'5
	Force Constant [N/m]	40	-		.8
	CB length [µm]	12	5	2	25
	CB width [µm]	30)	2	28
have ATAA muchas have been developed in	CB thickness [µm]	4.0)	3	.0
nese AFM probes have been developed in Ilaboration with nanotools®	AFM Support chip: Silico	n			
Extra Tall PointProbePlus AFM	Also av	vailable throu	ıgh nanoto	ools®	
scanning probes	Also av Tips	vailable throu	-	ools®	
scanning probes	Also av	vailable throu Radius [nm]	igh nanoto < 10 50 - 60	ools® 	
Extra Tall PointProbePlus AFM	Also av Tips	vailable throu Radius [nm] Height [µm]	< 10 50 - 60		
scanning probes	Also av Tips AFM Tip: Silicon	vailable throu Radius [nm] Height [µm]	< 10 50 - 60		SD-PXL- CONTSC
scanning probes	Also av Tips AFM Tip: Silicon	Radius [nm] Height [µm] . Different ver	 < 10 50 - 60 sions are a SD-PXL- 	vailable: SD-PXL-	
scanning probes	Also av Tips AFM Tip: Silicon AFM Cantilevers: Silicon	/ailable throu Radius [nm] Height [µm] . Different ver SD-PXL- NCL	< 10 50 - 60 sions are a SD-PXL- FM	vailable: SD-PXL- CONT	CONTSC
scanning probes	Also average of the second sec	Radius [nm] Height [µm] . Different ver SD-PXL- NCL 105	< 10 50 - 60 sions are a SD-PXL- FM 45	vailable: SD-PXL- CONT 7	CONTSC 8
scanning probes	Also av Tips <i>AFM Tip:</i> Silicon <i>AFM Cantilevers:</i> Silicon Resonance Frequency [kHz] Force Constant [N/m]	Radius [nm] Height [µm] . Different ver SD-PXL- NCL 105 60	 < 10 50 - 60 sions are a SD-PXL- FM 45 7.0 	vailable: SD-PXL- CONT 7 0.2	CONTSC 8 0.2



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	AFM Tip: Silicon	Radius [nm]	< 10	
1		Height [µm]	30 - 40	
	AFM Cantilevers: Silicon.			
		SD-AXL-NC		SD-AXL-CONT
	Resonance Frequency [kHz]	200	75	20
	Force Constant [N/m]	45	3.0	0.2
	CB length [µm]	240	240	240
	CB width [µm]	41	38	37
	CB thickness [µm]	7.3	3.0	1.2

Rounded AFM Tips R30

AFM Tip: Silicon	Radius [nm]	30	
	Height [µm]	10 - 15	
AFM Cantilevers: Silicon.	Different ver	sions are available	:
	SD-R30-NC	H SD-R30-FM	SD-R30-CONT
Resonance Frequency [kHz]	330	75	13
Force Constant [N/m]	42	2.8	0.2
CB length [µm]	125	225	450
CB width [µm]	30	28	50
CB thickness [µm]	4.0	3.0	2.0
Coating	-	25 nm PtIr on both	70 nm Au on
		sides	detector side
		(optional)	(optional)



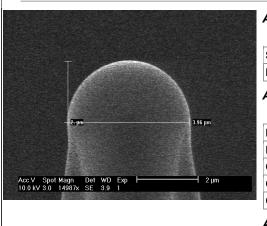
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Rounded AFM Tips R150

AFM Tip: S	ilicon Radius [nm]	90 (from front) / 160 (from side)
	Height [µm]	10 - 15	
AFM Cantil	evers: Silicon. Different ve	rsions are available	ə:
	SD-R150 NCH	- SD-R150- NCL	SD-R150- FM
Resonance F	requency [kHz] 330	190	75
Force Consta	ant [N/m] 42	48	2.8
CB length [µ	n] 125	225	225
CB width [µn	1] 30	38	28
CB thickness	ε [μm] 4.0	7.0	3.0
Coating	-	-	-
	SD-R150 CONT	- SD-R150- T3L450B]
Resonance F	requency [kHz] 13	20	
Force Consta	ant [N/m] 0.2	0.7	
CB length [µ	n] 450	450	
CB width [µn	ı] 50	53	j
CB thickness	[µm] 2.0	3.0	j
Coating	-	25 nm PtIr on both sides (optional)	-

Sphere AFM Tips



AFM Tips: Silicon / Silicon	Oxide. Differen	t versions are a	vailable:	
	S	м	L	
Sphere diameter [µm]	0.8	2.0	4.0	
Height [µm]	10 - 15			
	n. Different versions are available:			
AFM Cantilevers: Silicon.			1	
AFM Cantilevers: Silicon.	Different version SD-Sphere-NCH	ns are available SD-Sphere-FM	SD-Sphere-CONT	
AFM Cantilevers: Silicon. Resonance Frequency [kHz]			1	
	SD-Sphere-NCH	SD-Sphere-FM	SD-Sphere-CONT	
Resonance Frequency [kHz]	SD-Sphere-NCH 330	SD-Sphere-FM 75	SD-Sphere-CONT 13	
Resonance Frequency [kHz] Force Constant [N/m]	SD-Sphere-NCH 330 42	SD-Sphere-FM 75 2.8	SD-Sphere-CONT 13 0.2	

AFM Support chip: Silicon

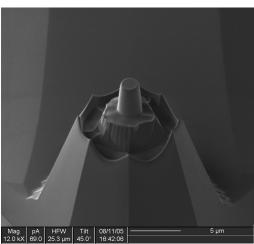


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	AFM Tip: Silicon	Plateau diam	eter [µm]	8 - 12	
		Height [µm]		15	
	AFM Cantilevers: Silicon	. Different ve	rsions ar	e available:	
		SD-PL-NCH	SD-PL-N	CL SD-PL-FM	SD-PL-CONT
	Resonance Frequency [kHz]	330	190	75	13
	Force Constant [N/m]	42	48	2.8	0.2
	CB length [µm]	125	225	225	450
	CB width [µm]	30	38	28	50
	CB thickness [µm]	4.0	7.0	3.0	2.0
N34C 5 μn	Coating	30 nm Al on detector side (optional)	-	30 nm Al on detector side (optional) or 25 nm PtIr on both sides	(optional) or 70 nm Au on
				(optional)	(optional)

Plateau AFM Tips



A <i>FM Tip:</i> Silicon	Plateau diameter [µm]	1.8 (typical)		
	Rod height [µm]	> 2.0		
	Overall height [µm]	10 - 15		
AFM Cantilevers: Silicon.	Different versions ar	e available:		
	SD-PL2-NCH	SD-PL2-NCL		
Resonance Frequency [kHz]	330	190		
Force Constant [N/m]	42	48		
CB length [µm]	125	225		
CB width [µm]	30 38			
CB thickness [µm]	4.0 7.0			
Coating	30 nm Al on detector side (optional)			



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D) Ultra-Short AFM Cantilevers

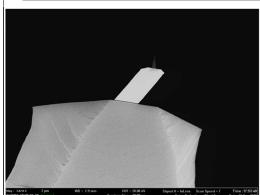
Short Tipless AFM Cantilevers				
AFM Tip: none AFM Cantilevers: Quartz	z like Different v	versions are ava	ulable [.]	
Ar in Cantilevers. Qualiz	SD-USC-F5- k30-TL	SD-USC-F2- k3-TL	SD-USC-F1.2- k7.3-TL	
Resonance Frequency [kHz]	5'000	2'000	1'200	
Force Constant [N/m]	30	3	7.3	
CB length [µm]	10	10	20	
CB width [µm]	5	5	10	
CB thickness [µm]	0.68	0.28	0.67	
at Magn Det WD Exp 2,µm 7993x SE 8.6 1	3	0 nm Au on both sid	es	
	SD-USC-F1.5- k0.6-TL	SD-USC-F1.2- k0.15-TL	SD-USC-F0.3- k0.3-TL	
Resonance Frequency [kHz]	1'500	1'200	330	
Force Constant [N/m]	0.6	0.15	0.3	
CB length [μm]	7	7	20	
CB width [µm]	3	2	10	
CB thickness [µm]	0.10	0.08	0.19	
Coating	20 nm Au o	n both sides	30 nm Au on both sides	



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Ultra-Short Silicon Nitride AFM Cantilevers



These AFM probes have been developed in collaboration with nanotools®



	Radius [nm]	< 10				
	Height [µm]	> 2				
AFM Cantilevers: Silicon	Nitride. Diffe	erent versior	ns are availa	ıble:		
	SD-USC-SiN 0.5MHz	SD-USC-SiN 1.2MHz	SD-USC-SIN SD-USC-SIN SD-US 1.2MHz 3MHz 6MI			
Resonance Frequency [kHz]	500	1'200	3'000	6'000		
Force Constant [N/m]	0.2	0.4	0.9	45		
CB length [µm]	13.5	6.8	4.2	9.5		
CB width [µm]	4.5	4.5	2.3	4.5		
CB thickness [µm]	0.10	0.06	0.06	0.50		
Coating	40 nm Au on detector side	30 nm Au on detector side		70 nm Au on detector side		



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AMI/	AFM Tip: High Density C	arbon / Diamon	d Like Carbon (F	IDC/DLC)
		Radius [nm]	< 10	
		Height [µm]	2.5	
	AFM Cantilevers: Silicor	Nitride. Differe	nt versions are a	vailable:
T	Hard cantilevers (for air)	SD-HFP-H27R	SD-HFP-H45R	SD-HFP-HU45R
	Resonance Frequency [kHz]	2'700	4'500	4'500
	Force Constant [N/m]	40	47	32
	CB length [µm]	20	15	20
	CB width [µm]	10	5	10
hese AFM probes have been developed in ollaboration with nanotools®	CB thickness [µm]	0.77	0.77	0.16
	CB cross-section	rectangular	rectangular	U-profile
🚺 nanotools	Coating	30) nm Al on detector s	ide
scanning probes	Soft cantilevers (for liquid)	SD-HFP-S04AuD	SD-HFP-S07AuD	SD-HFP-S08TiD
	Resonance Frequency [kHz]	360	660	800
	Force Constant [N/m]	0.4	0.6	0.5
	CB length [µm]	20	15	15
	CB width [µm]	10	5	5
	CB thickness [µm]	0.16	0.16	0.16
	CB cross-section		rectangular	'
	Coating	30 nm Au or	detector side	30 nm Ti on detector side



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E) Special AFM Probes

AFM Tip: Silicon	Radius [nm]	< 10	
	Height [µm]	15 - 20	
AFM Cantilevers: Silicon.	Different ver	sions are	available:
	SD-ATEC	-NCLwG	SD-ATEC-NCLwGR
Resonance Frequency [kHz]	15	5	155
Force Constant [N/m]	33	3	33
CB length [µm]	25	0	250
CB width [µm]	40)	40
CB thickness [µm]	7.0	0	7.0
			30 nm Al on detector sig

	AFM Tip: Hollow SiO ₂	Radius [nm]	150 (including	coating)
		Height [µm]	16	
		Setback [µm]	75	
		Tip Coating	250 nm Al (op	tionally without coating
	_	SD-HTT-NC		SD-HTT-CONT
	Resonance Frequency [kHz]	58		11
	Force Constant [N/m]	43		0.6
	CB length [µm]	400)	400
Acc.V Spot Magn 20 μm	CB width [µm]	150	0 150	
10.0 kV 3.0 1015x Pyrex-Si 67618	op width [bin]		-	



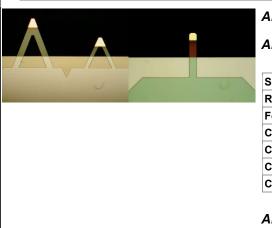
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	AFM Tip: Hole instead	Size [µm] 4	x 4	
	of tip	·		
	AFM Cantilevers: Silicon	. Multi-cantilever	s chip with 3 car	ntilevers:
		SD-PD-TRI NCH	SD-PD-TRI <i>FM</i>	SD-PD-TR CONT
	Resonance Frequency [kHz]	330	75	13
•	Force Constant [N/m]	42	2.8	0.2
	CB length [µm]	100	210	500
	CB width [µm]	50	30	30
	CB thickness [µm]	2.7	2.7	2.7

uniqprobe Tipless AFM Cantilevers



AFM Tip: none

AFM Cantilevers: Quartz-like. Different versions are available:

	SD-qp-l	BioT-TL	SD-qp-CONT-TL	SD-qp-SCONT-TL	
Shape of the cantilevers	trian	gular	rectar	ngular	
Resonance Frequency [kHz]	55	16	32	13	
Force Constant [N/m]	0.4	0.09	0.1	0.01	
CB length [µm]	100	200	130	130	
CB width [µm]	2x 19	2x 33	40	40	
CB thickness [µm]	0.9	0.9	0.75	0.35	
Coating	60 nm Au on detector side (partial coating)*				
* Optionally available	without o	oating (u	ncoated cantilever	rs are transparent!)	
AFM Support chip: Silicor	h with A	lignmer	nt Grooves		



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uniqprobe Tipless AFM Cantilevers Arrays

AFM Cantilevers: Qu	artz-like. Different versions	are available:
	SD-qp-TL8a	SD-qp-TL8b
Shape of the cantilevers	rect	angular
Resonance Frequency [k	Hz] 4.0	2.3
Force Constant [N/m]	0.02	0.004
CB length [µm]	500	500
CB width [µm]	100	100
CB thickness [µm]	1.2	0.7
Number of cantilevers	8	8
Pitch [µm]	250	250
Coating sample facing s	de 30	nm Au*
Coating detector side	20	nm Au*



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MAC Mode AFM Cantilevers for Keysight / Agilent / Molecular Imaging

	SD-MAC-Ty SD-MAC-Ty		D-MAC-Type7 D-MAC-Type8
Material	Silicon		Quartz-like
Radius [nm]	< 10		< 10
Height [µm]	10 – 15		7
AFM Cantilevers: Different	t versions are a	vailable:	
	SD-MAC-Type2	SD-MAC-Type7	SD-MAC-Type
Material	Silicon	Quartz-like	Quartz-like
Resonance Frequency [kHz]	75	43	48
Force Constant [N/m]	2.8	0.14	0.3
CB length [µm]	225	125	125
CB width [µm]	30	35	35
CB thickness [µm]	3.0	0.75	1.0
Coating	75 nm Ni on detector side	40 nm Ni or	detector side
		SD-MAC-Type9	
	CB 1	CB 2	CB 3
Material		Silicon	
Resonance Frequency [kHz]	90	130	65
Force Constant [N/m]	1.0	2.0	0.6
CB length [µm]	110	90	130
CB width [µm]	33	33	33
CB thickness [µm]	1.0	1.0	1.0
Coating	60	nm Ni on detector	side



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Silicon Nitride Arrays with AFM Tips (Nanolnk, Inc[®] compatible)

	AFM Tip: Silicon Nitride	Radius [nm]<	10 5	
	AFM Cantilevers: Silicon	Nitride. Differen	t versions are av	vailable:
		SD-PNP-Array1	SD-PNP-Array2 up / down left–right	SD-PNP-Array3
	Shape of the cantilevers	recta	ngular	triangular
	Resonance Frequency [kHz]	70	30 / 17-30	70
NAME AND ADDRESS OF TAXABLE PARTY.	Force Constant [N/m]	0.5	0.2 / 0.07-0.2	0.3
	CB length [µm]	100	150 / 200-150	100
	CB width [µm]	40	50 / 45-50	2x 14
	CB thickness [µm]	0.55	0.55	0.55
	Number of cantilevers	18	18 / 3-3	12
	Pitch [µm]	60	70 / 70-70	66
	Coating	60	nm Au on detector	side
NanoInk, Inc [®] is a registered trademark of NanoInk, Inc.	AFM Support chip: Pyrex	glass		

nAmbition Silicon Nitride Arrays

AFM Tip: Silicon Nitride	Radius [nm] < 15	
	Height [µm] 3.5	
AFM Cantilevers: Silicon	Nitride. Different vers	sions are available:
	SD-nAmbition-Array Reference CB (45° tilte Measurement CB	
Shape of the cantilevers	re	ectangular
Resonance Frequency [kHz]	23 / 94	11 / 42
Force Constant [N/m]	0.03 / 0.17	0.01 / 0.05
CB length [µm]	100 / 50	144 / 75
CB width [µm]	30 / 20	30 / 20
CB thickness [µm]	0.24	0.24
Number of cantilevers	2 / 3 (1 without tip)	2 / 8 (1 without tip)
Pitch [µm]	200	100
Coating	30 nm Au on both sides	
AFM Support chip: Pyrex	glass	



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F) Diverse (AFM related)

Alignment Chip Alignment Chip features: - reproducible positioning of the AFM probe - easy tip exchange without readjustment of AFM cantilever deflection system - fits on all NANOSENSORS™ AFM probes of the PointProbe® Plus and PointProbe® Plus XY-Alignment Series - high stability because of a chromium coating SD-ALIGN Dimensions [µm] 3400 x 2900 Thickness without probe [µm] 525 Thickness with mounted probe [µm] 700 Tip repositioning accuracy (same probe) [µm] ± 2 XY-Align. Series: Tip repositioning accuracy (any probe) [µm] ± 8

2D200 Pitch-Grating



Chip: Silicon	Chip size [mm]	5 x 7	
	Active area size [µm]	100 x 100	
Lattice:			
Pitch [nm]		200	
Accuracy of pyramid p	osition [nm]	± 10	
Accuracy of pyramid pitch (10x10 μm ² scan) [%]		± 0.1	
Accuracy of pyramid pitch (100x100 µm ² scan) [%]		±0.01	
Pyramids: Edge length of square	pyramids [nm]	approx 100	
Sidewall angle (versus wafer surface) [°]		54.7	
Accuracy of sidewall angle [°]		± 0.5	
Accuracy of sidewall a			



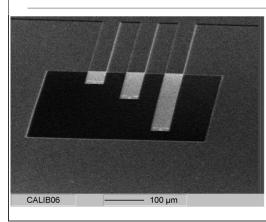
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2D300 Pitch-Grating Chip : Silicon Chip size [mm] 5 x 7 Active area size [µm] 100 x 100 Lattice: Pitch [nm] 300

10 m 1		
STIPN	Accuracy of pyramid position [nm]	± 10
DPIRC	Accuracy of pyramid pitch (10x10 μm ² scan) [%]	± 0.1
	Accuracy of pyramid pitch (100x100 μm ² scan) [%]	±0.01
5D500	Pyramids:	
Logic Street Street	Edge length of square pyramids [nm]	approx 100
	Sidewall angle (versus wafer surface) [°]	54.7
	Accuracy of sidewall angle [°]	± 0.5
	Depth of pyramids [nm]	approx 70

CalibLever



TYPE

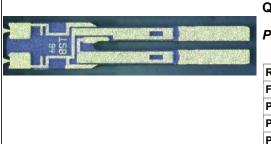
AFM Tip: none

AFM Cantilevers: Multi-cantilevers chip with 3 AFM cantilevers:

	SD-CalibLever CB450	SD-CalibLever CB200	SD-CalibLever CB80
Resonance Frequency [kHz]	14	65	330
Force Constant [N/m]	0.21	2.1	25
CB length [µm]	465	215	95
CB width [µm]	50	50	50
CB thickness [µm]	2.15	2.15	2.15

AFM Support chip: Silicon

1		
A	Tuning	
Ullartz	ilinina	FOLK
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Quartz Tuning Fork Type E158-24

Properties:

	SD-TF			
Resonance Frequency [kHz]	approx. 32.768			
Force Constant [N/m]	approx. 1900			
Prong length [µm]	2300			
Prong width [µm]	216			
Prong thickness [µm]	125			

Optionally available mounted on a ceramic plate (SD-QTFM)



Quality Factor (Q-Factor): better than 3% Service available for all products with cantilevers having a Force

Measurement traceable with PTB certified Force Standard

Special Developments List (version 6.1)

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Spring Constant Calibrated AFM Cantilevers Determination of the mechanical properties of AFM cantilevers by 10,18 14,75 Laser Doppler Vibrometry And Annual Telan - PER Data: **Resonance Frequency** Force Constant Quality Factor (Q-Factor) Accuracy: Resonance Frequency: better than 0.1 % Force Constant: better than 5 % (k < 1 N/m) better than 10% (1 N/m < k < 10 N/m) better than 20% (10 N/m < k < 100 N/m)

Constant < 100 N/m

Version 6.1 (2024.12.12)



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Stainless Steel AFM Probes Box (Gel and plastics free)





NANOSENSORS[™] developed a box fabricated solely from metal avoiding the usage of adhesion gel and plastics. These boxes are especially suited for applications that are extremely sensitive to organic molecules such as tip enhanced infra-red spectroscopy.

The box can be used for transport and storage.

Each box has a capacity of 10 AFM probes that are individually fixed by a movable clamp.

Product order codes are marked with 'MB'. Apart from packaging the products are identical to their base products:

	PPP- CONTPt-MB	PPP- EFM-MB	PPP- NCSTPt-MB	PPP- NCLPt-MB
Resonance Frequency [kHz]	13	75	160	190
Force Constant [N/m]	0.2	2.8	7.4	48
CB length [µm]	450	225	150	225
CB width [µm]	50	28	27	38
CB thickness [µm]	2.0	3.0	2.8	7.0
Coating	25 nm PtIr5 on both sides			

	PPP-	PPP-	PPP-	PPP-
	NCHPt-MB	CONTAu-MB	NCSTAu-MB	NCHAu-MB
Resonance Frequency [kHz]	330	13	160	330
Force Constant [N/m]	42	0.2	7.4	42
CB length [µm]	125	450	150	125
CB width [µm]	30	50	27	30
CB thickness [µm]	4.0	2.0	2.8	4.0
Coating	25 nm PtIr5 on both sides		u on both side	s

	PPP- NCHAu25-MB	PPP- NCHR-MB	ATEC- NCAu-MB	PtSi- FM-MB
Resonance Frequency [kHz]	250	330	335	75
Force Constant [N/m]	35	42	45	2.8
CB length [µm]	125	125	160	225
CB width [µm]	30	30	45	28
CB thickness [µm]	3.8	4.0	4.6	3.0
Coating	25 nm Au on tip side, 70 nm Au on detector side	30 nm Al on detector side	Au on both sides	25 nm PtSi on both sides



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	PtSi- NCH-MB
Resonance Frequency [kHz]	330
Force Constant [N/m]	42
CB length [µm]	125
CB width [µm]	30
CB thickness [µm]	4.0
Coating	25 nm PtSi on both sides

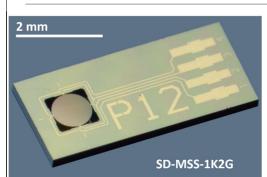


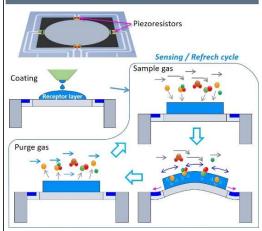
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G) Nanomechanical Sensors

Membrane-type Surface-stress Sensor (SD-MSS)





(i) for gas/odor sensing

Туре:

Silicon membrane platform supported with four beams on which piezoresistors are embedded. SD-MSS-1K2GP has a passivation on the electrodes for "liquid" applications.

Applications:

Working Principle:

Electronic nose, gas/odor sensing, human breath analysis *e.g.*, for cancer research (note: for these applications, an appropriate receptor layer must be coated on the membrane by user).

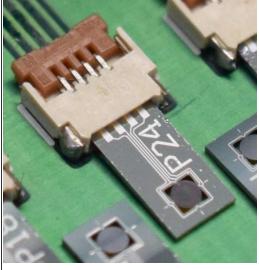
Surface-stress yielded by the coated receptor layer absorbing gas/odor molecules deforms the membrane and the supporting beams, which induces resistance change of the piezoresistor. By measuring the resistance change, the magnitude of the target parameter can be estimated.

	SD-MSS-1K2G	SD-MSS-1K2GP		
Membrane size [µm]	1000 (round)			
Membrane thickness [µm]	2.8 (typical)			
Chip dimensions [mm]	5.5 x 2.5 x 0.3			
Resistance value [kΩ]	2 – 6			
Electric configuration	Full bridge, 4 pads, 0.5 mm pitch			
Coating	No			
Electrode passivation	No Yes			

Easy Plug-in Connection:

These sensors fit to a commercial FPC (Flexible Printed Circuit) / FFC (Flexible Flat Cable) connectors with 0.5 mm pitch.

For more information please visit http://mss-sensor.com

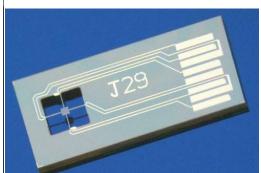




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Membrane-type Surface-stress Sensor (SD-MSS)

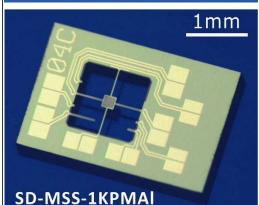


(ii) for static/pulsed-field torque magnetometry

Type: Silicon membrane platform supported with four beams, designed to rotate along with a torsional axis. A yielded torque is measured by embedded piezoresistors on the bending axis.

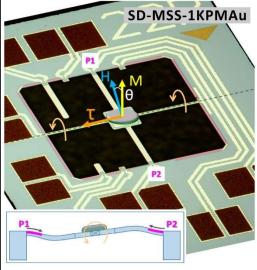
Applications:

Nanomechanical sensing, material assessment, static/pulsed-field torque magnetometry, force sensing, etc.



Working Principle: A sample attached to the platform tends to align with the applied magnetic field, which twists the torsional axis and bends the bending axis on which piezoresisors are embedded. By measuring the resistance change, the magnitude of the yielded force can be estimated.

	SD-MSS-1KTM	SD-MSS-1KPMAI	SD-MSS-1KPMAu	
Membrane size [µm]	200 (square)			
Membrane thickness [µm]	2.8 (typical)			
Chip dimensions [mm]	5.5 x 2.5 x 0.3 3.0 x 2.0 x 0.3			
Resistance value [kΩ]	0.3 – 1.2			
Electric configuration	Separated, 8 pads, 0.25 (0.5) mm pitch gluing Gold pads for bonding or gluing			
Piezoresistive cantilever	No	120 μm, 400 μm		



For more information please visit http://mss-sensor.com



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MSS 8 Channel Readout Module (SD-MSS-8RM)

